

APPLICATIONS

- Aerosol research
- Indoor and outdoor particle measurement
- Workplace measurement
- Test of filters, air cleaners
- Cloud research
- Emission and immission measurement
- Inhalation measurement
- Calibration



OUR CORE COMPETENCIES

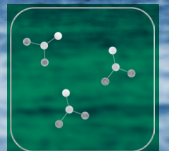
- Filter test systems
- Aerosol spectrometer systems
- Fine dust monitoring systems
- Nanoparticle measurement systems
- Particle generation systems
- Dilution systems
- Clean room particle technology
- Special developments
- Calibration systems
- Services
- Training courses and seminars

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NANOPARTICLE MEASURING DEVICES



OVERVIEW

UF-CPC SYSTEM

condensation particle counter

UF-CPC 50

$C_{N\text{Max}}$: 10^4 particles/cm³ (single count mode)*¹
 d_p : 4–5,000 nm



UF-CPC 100

$C_{N\text{Max}}$: 10^5 particles/cm³ (single count mode)*¹
 d_p : 4–10,000 nm

UF-CPC 200

$C_{N\text{Max}}$: $2 \cdot 10^6$ particles/cm³ (single count mode)*¹
 d_p : 4–10,000 nm

ENVI-CPC SYSTEM

condensation particle counter for particle concentration measurement according to EN 16976:2024

d_p : 4–5,000 nm
 $D50 \approx 10$ nm

ENVI-CPC 50

$C_{N\text{Max}}$: 10^4 particles/cm³ (single count mode)*¹



ENVI-CPC 100

$C_{N\text{Max}}$: 10^5 particles/cm³ (single count mode)*¹

ENVI-CPC 200

$C_{N\text{Max}}$: $2 \cdot 10^6$ particles/cm³ (single count mode)*¹

*¹ $C_{N\text{Max}}$: 10^7 particles/cm³ (nephelometric mode)

DEMC SYSTEM

differential electrical mobility classifier with short/long column according to ISO 15900:2020

DEMC 1000

d_p : 4–600 nm

DEMC 2000

d_p : 8–1,400 nm

DEMC ---- X

integrated soft X-ray neutralizer



U-SMPS SYSTEM

universal scanning mobility particle sizer, different configuration possible

U-SMPS 1050/1100/1200

d_p : 4–440 nm

U-SMPS 1700

d_p : 2–440 nm



U-SMPS 2050*²/2100*²/2200

d_p : 8–1,200 nm

U-SMPS 2700

d_p : 6–1,200 nm

U-SMPS ---- X

integrated soft X-ray neutralizer

*²with ENVI-CPC System compliant to CEN/TS 17434:2020

U-RANGE 2000

continuous measurement of particles
 U-SMPS SYSTEM in combination with FIDAS[®] 200
 (also possible with PROMO[®] LED 2000)

d_p : 8–40,000 nm

NEUTRALIZER

KR-85-370

radioactive source



XRC 049

X-ray source



CHARME[®]

reference aerosol electrometer

$C_{N\text{Max}}$: $1.6 \cdot 10^7$ particles/cm³
 d_p : >2 nm



AQ GUARD SMART 2000

air quality analyzer for monitoring nanoparticles

$C_{N\text{Max}}$: 10^8 particles/cm³
 d_p : > 10 nm

